

# High-speed double diode

HB181

## FEATURES

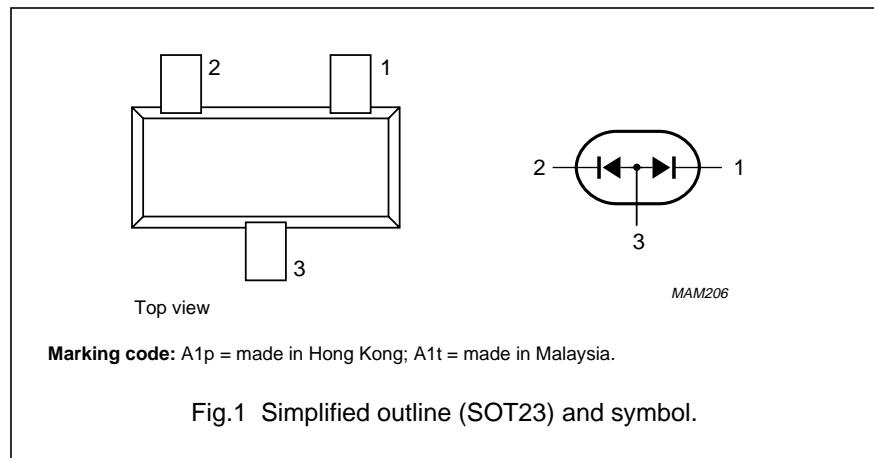
- Small plastic SMD package
- High switching speed: max. 4 ns
- Continuous reverse voltage: max. 75 V
- Repetitive peak reverse voltage: max. 85 V
- Repetitive peak forward current: max. 450 mA.

## APPLICATIONS

- High-speed switching in thick and thin-film circuits.

## PINNING

PIN	DESCRIPTION
1	cathode (k1)
2	cathode (k2)
3	common anode



Marking code: A1p = made in Hong Kong; A1t = made in Malaysia.

Fig.1 Simplified outline (SOT23) and symbol.

## LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
<b>Per diode</b>					
$V_{RRM}$	repetitive peak reverse voltage		–	85	V
$V_R$	continuous reverse voltage		–	75	V
$I_F$	continuous forward current	single diode loaded; note 1; see Fig.2	–	215	mA
		double diode loaded; note 1; see Fig.2	–	125	mA
$I_{FRM}$	repetitive peak forward current		–	450	mA
$I_{FSM}$	non-repetitive peak forward current	square wave; $T_j = 25^\circ\text{C}$ prior to surge; see Fig.4			
		$t = 1 \mu\text{s}$	–	4	A
		$t = 1 \text{ ms}$	–	1	A
		$t = 1 \text{ s}$	–	0.5	A
$P_{tot}$	total power dissipation	$T_{amb} = 25^\circ\text{C}$ ; note 1	–	250	mW
$T_{stg}$	storage temperature		–65	+150	°C
$T_j$	junction temperature		–	150	°C

## Note

1. Device mounted on an FR4 printed-circuit board.

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## ELECTRICAL CHARACTERISTICS

$T_j = 25^\circ\text{C}$  unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MAX.	UNIT
<b>Per diode</b>				
$V_F$	forward voltage	see Fig.3 $I_F = 1 \text{ mA}$ $I_F = 10 \text{ mA}$ $I_F = 50 \text{ mA}$ $I_F = 150 \text{ mA}$	715 855 1 1.25	mV mV V V
$I_R$	reverse current	see Fig.5 $V_R = 25 \text{ V}$ $V_R = 75 \text{ V}$ $V_R = 25 \text{ V}; T_j = 150^\circ\text{C}$ $V_R = 75 \text{ V}; T_j = 150^\circ\text{C}$	30 1 30 50	nA $\mu\text{A}$ $\mu\text{A}$ $\mu\text{A}$
$C_d$	diode capacitance	$f = 1 \text{ MHz}; V_R = 0$ ; see Fig.6	2	pF
$t_{rr}$	reverse recovery time	when switched from $I_F = 10 \text{ mA}$ to $I_R = 10 \text{ mA}$ ; $R_L = 100 \Omega$ ; measured at $I_R = 1 \text{ mA}$ ; see Fig.7	4	ns
$V_{fr}$	forward recovery voltage	when switched from $I_F = 10 \text{ mA}$ ; $t_r = 20 \text{ ns}$ ; see Fig.8	1.75	V

## THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th j-tp}$	thermal resistance from junction to tie-point		360	K/W
$R_{th j-a}$	thermal resistance from junction to ambient	note 1	500	K/W

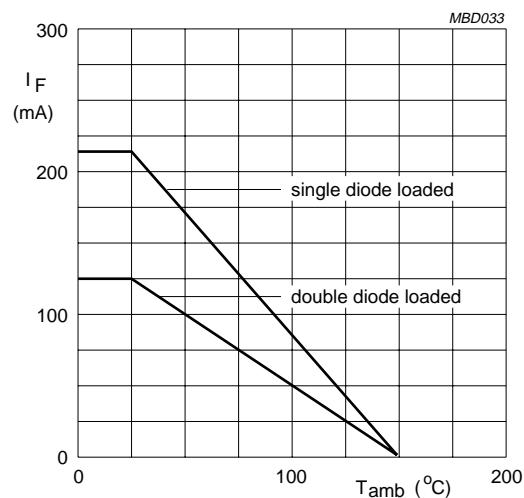
### Note

1. Device mounted on an FR4 printed-circuit board.

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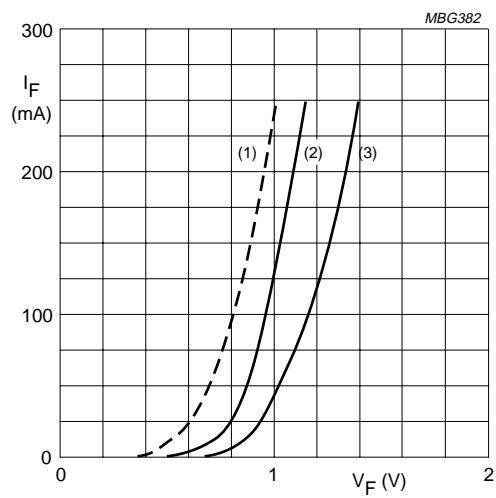
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## GRAPHICAL DATA



Device mounted on an FR4 printed-circuit board.

Fig.2 Maximum permissible continuous forward current as a function of ambient temperature.

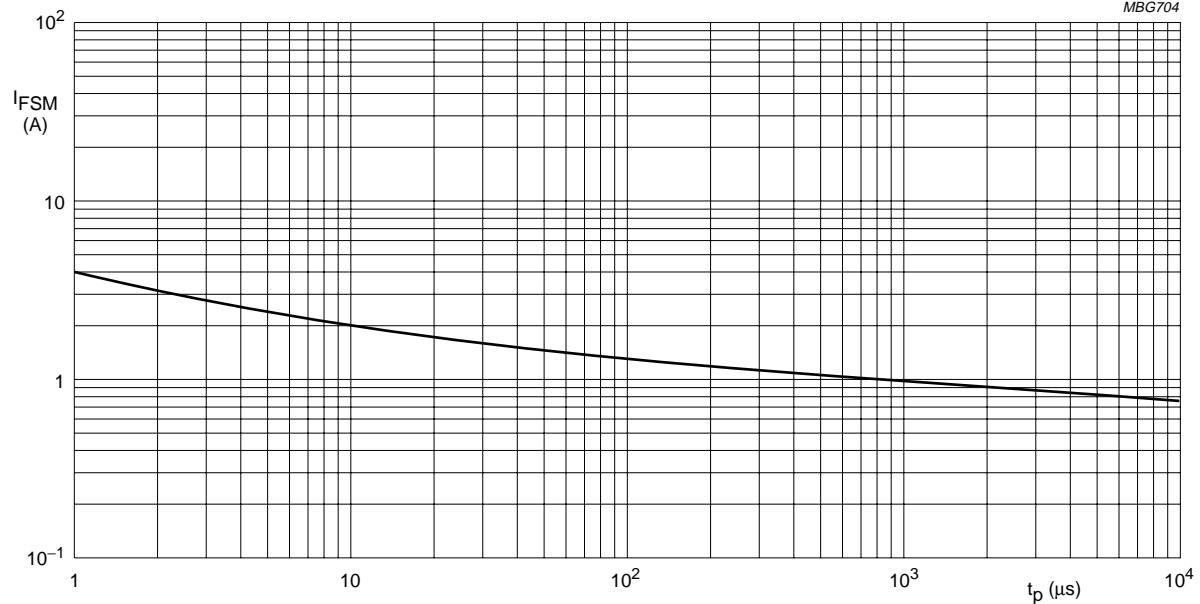


(1)  $T_j = 150$   $^{\circ}$ C; typical values.

(2)  $T_j = 25$   $^{\circ}$ C; typical values.

(3)  $T_j = 25$   $^{\circ}$ C; maximum values.

Fig.3 Forward current as a function of forward voltage.



Based on square wave currents.  
 $T_j = 25$   $^{\circ}$ C prior to surge.

Fig.4 Maximum permissible non-repetitive peak forward current as a function of pulse duration.

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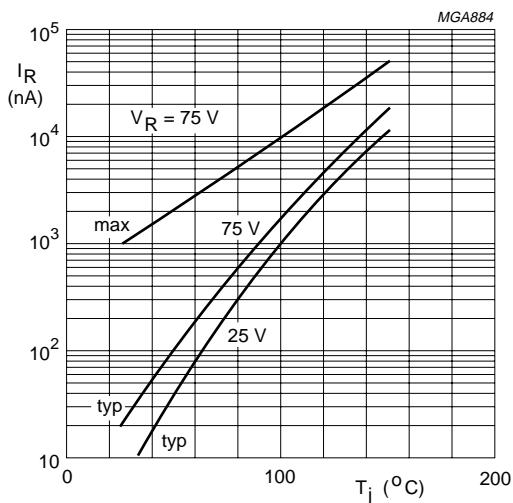
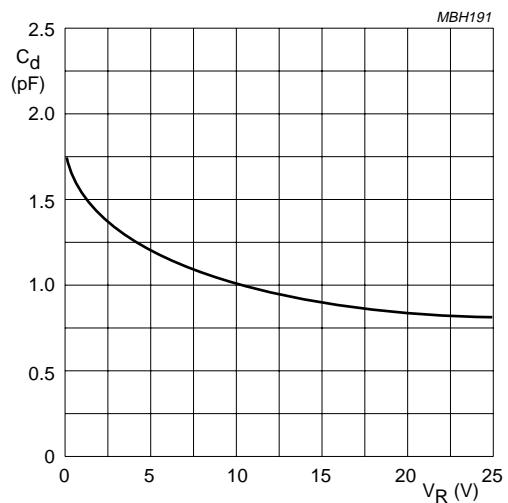


Fig.5 Reverse current as a function of junction temperature.

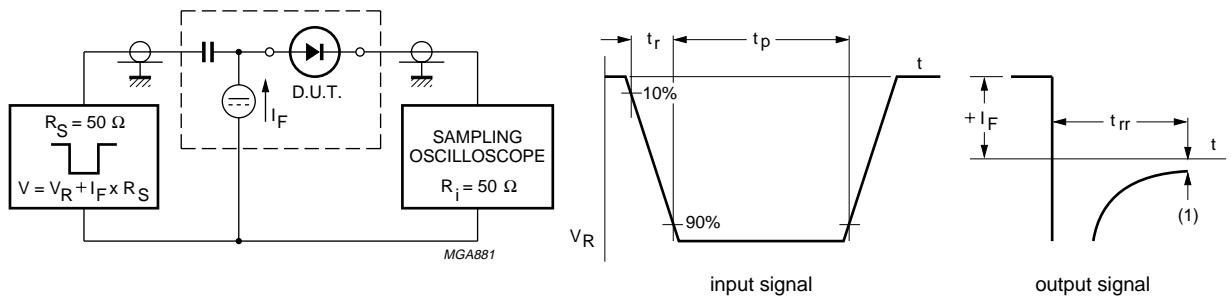


$f = 1\text{ MHz}; T_j = 25\text{ }^\circ\text{C}.$

Fig.6 Diode capacitance as a function of reverse voltage; typical values.

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(1)  $I_R = 1 \text{ mA}$ .

Fig.7 Reverse recovery voltage test circuit and waveforms.

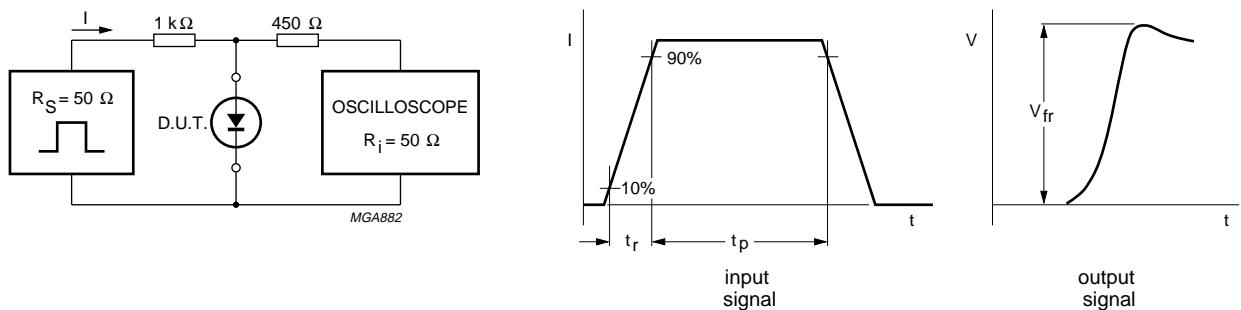


Fig.8 Forward recovery voltage test circuit and waveforms.

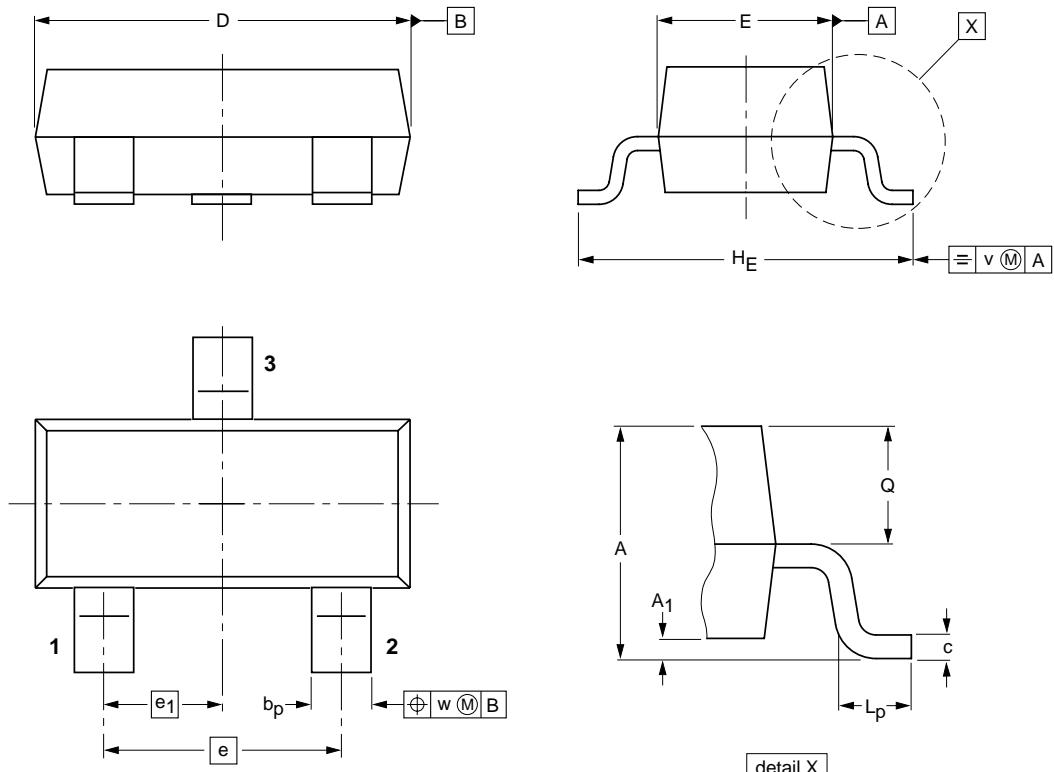
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## PACKAGE OUTLINE

Plastic surface mounted package; 3 leads

SOT23



0 1 2 mm  
scale

## DIMENSIONS (mm are the original dimensions)

UNIT	A	A <sub>1</sub> max.	b <sub>p</sub>	c	D	E	e	e <sub>1</sub>	H <sub>E</sub>	L <sub>p</sub>	Q	v	w
mm	1.1 0.9	0.1	0.48 0.38	0.15 0.09	3.0 2.8	1.4 1.2	1.9	0.95	2.5 2.1	0.45 0.15	0.55 0.45	0.2	0.1

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT23						97-02-28